## Search Notes



| Application/Control No | <b>Appl</b> | icatio | n/Con | trol | No |
|------------------------|-------------|--------|-------|------|----|
|------------------------|-------------|--------|-------|------|----|

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Applicant(s)/Patent Under Reexamination

ISHIKAWA ET AL.

Examiner José V Chen Art Unit

illine:

3637

## SEARCHED

| Class | Subclass            | Date     | Examiner |
|-------|---------------------|----------|----------|
| 108   | 22, 20, 21, 143, 94 | 05/26/09 | jvc      |
| 74    | 16, 825, 813r       | 05/26/09 | jvc      |
| 248   | 349.1               | 05/26/09 | jvc      |
|       | updated             | 11/12/09 | jvc      |
|       | updated             | 05/06/10 | jvc      |

## SEARCH NOTES

| Search Notes                  | Date     | Examiner |
|-------------------------------|----------|----------|
| for and back cit for pert art | 05/26/09 | jvc      |
| updated                       | 11/12/09 | jvc      |
| updated                       | 05/06/10 | jvc      |
| int text search hist          | 05/06/10 | jvc      |

## INTERFERENCE SEARCH

| Class | Subclass | Date     | Examiner |
|-------|----------|----------|----------|
| 108   | 20, 94   | 05/06/10 | jvc      |
| 248   | 349.1    | 05/06/10 | ivc      |

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